

<b>Notice of References Cited</b>	Application/Control No. 10/661,987		Applicant(s)/Patent Under Reexamination KRAUSE, KEVIN R.	
	Examiner BINH K. TIEU		Art Unit 2614	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,265,145	11-1993	Lim, Boon C.	379/88.2
*	B	US-6,882,838	04-2005	Lee et al.	455/417
*	C	US-6,459,780	10-2002	Wurster et al.	379/142.02
*	D	US-5,533,102	07-1996	Robinson et al.	379/88.25
*	E	US-6,178,232	01-2001	Latter et al.	379/88.21
*	F	US-5,511,111	04-1996	Serbetcioğlu et al.	379/88.01
*	G	US-5,498,841	03-1996	Allen, Derek R.	181/137
*	H	US-6,804,330	10-2004	Jones et al.	379/88.01
*	I	US-2005/0117733	06-2005	Widger et al.	379/221.05
*	J	US-5,999,611	12-1999	Tatchell et al.	379/211.02
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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